

## OPTEXC Tutorial Series

## Introduction to Near-Edge X-ray Absorption Fine-Structure (NEXAFS) Spectroscopy

NEXAFS spectroscopy is a synchrotron-based technique that is used to study the electronic structure and microstructure of materials. It is particularly well-suited to studying organic thin film samples such as organic semiconductor films used in devices. In this talk I will give an introduction to the fundamentals of NEXAFS spectroscopy and provide examples from my group of what can be learnt. Of relevance to the IRTG, the Australian Synchrotron (pictured) is located next to the main campus of Monash University in Melbourne, with two beamlines that are dedicated to such measurements.

Date: Monday, 20<sup>th</sup> November 2023 | Time: 8:15 am (CET) / 6:15 pm (AEDT) Room: S70 (NWII) / Zoom ID: 631 3850 0251 Code: 484363

